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Sensors Fault Diagnosis Trends and Applications

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Message from the Guest Editor

Dear Colleagues,

Fault diagnosis has always been a concern for industry. In general, diagnosis in complex systems requires the acquisition of information from sensors and the processing and extracting of required features for the classification or identification of faults. Therefore, fault diagnosis of sensors is clearly important as faulty information from a sensor may lead to misleading conclusions about the whole system. As engineering systems grow in size and complexity, it becomes more and more important to diagnose faulty behavior before it can lead to total failure. In the light of above issues, this Special Issue is dedicated to trends and applications in modern-sensor fault diagnosis.

Dr. Piotr Witczak *Guest Editor*













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Message from the Editor-in-Chief

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